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PSS LDBI3072-TO56-P

LD Integrated Reliability System

Product Introduction

PSS LD integrated reliability system is used for burn-in screening and reliability and life analysis of low-power visible light LD TO devices, which effectively improves the quality of TO products after screening. The system can support the burn-in of 3072 devices, and realize the burn-in of devices by providing constant current to LD devices. The system can display the burn-in current, direct voltage, backlight current, temperature, power and other parameters in real time and display them visually, which is convenient for observing the abnormal situation in the burn-in process. The universal burn-in board is compatible with other automation equipment of our company.

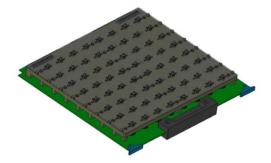
Product Application

- It can be used for burn-in screening of visible light LD TO devices in mass production.
- Analysis of long-term reliability failure test



Product Features

- Provide completely independent driving current for each burn-in board.
- The integrated burn-in box comes with two independent boxes, which can be completely controlled independently, with high heating speed and no overshoot; Support over-temperature protection
- ACC constant current mode and APC constant backlight mode are optional.
- As a general carrier, burn-in board can realize direct material transfer at different stations of disk testing and burn-in, and improve production efficiency; An NTC thermistor is installed next to each TO56 slot to detect the temperature in real time.



• Each burn-in board can be equipped with a pre-installation optical detection board to monitor the optical power before burn-in in real time and test the LIV characteristics regularly.

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• Reliable ESD/EOS protection ensures the safety of devices during burn-in and supports open circuit and short circuit protection.





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Upper computer software

Ith repeatability (typical test)

• Software switching supports burn-in of various types of packaged LD devices, and supports TO56 fixed 3-pin switching.

Technical Parameter

Description/Value				
TO56, support TO56 fixed 3-pin switching				
3072 road, 2 independent temperature zones				
0-150mA				
0~7V				
0~7V				
0-2000uA				
25~120℃, ±1℃@60℃, 10KNTC				
10~100mW				
380-900 nm				
45~90℃				
65℃~100℃				
Temperature uniformity: 2°C (no load), temperature				
stability: 0.5°C				
Heating rate: 2℃/Min, cooling rate: 1℃/Min.				
AC 380V/50HZ				
1400 x 1800 x 1200(mm)				

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